WHAT IS CLAIMED IS:

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1. A semiconductor device, comprising:

a light-receiving element having a light-receiving face formed on a main surface of a semiconductor substrate;

an antireflection coating formed so as to cover the light-receiving face of said light-receiving element, and formed by a prescribed layer for preventing reflection of incident light;

a protection film formed on said antireflection coating and protecting said antireflection coating; and

a mold material formed on said semiconductor substrate so as to directly cover said protection film.

- 2. The semiconductor device according to claim 1, wherein said protection film has an index of refraction different from that of said mold material by at most 0.3.
 - 3. The semiconductor device according to claim 1, wherein said protection film includes a silicon oxide film.
 - 4. The semiconductor device according to claim 1, wherein said protection film includes a polyimide-based resin.
- 5. The semiconductor device according to claim 1, further comprising a signal processing circuit portion for processing a prescribed signal, formed in a region of said semiconductor substrate different from a region where said light-receiving element is formed.
- 6. The semiconductor device according to claim 5, further comprising a first insulating film formed so as to cover said signal processing circuit portion, wherein

said protection film includes a film formed with a layer identical to said first insulating film.

7. The semiconductor device according to claim 6, further comprising a first interconnection formed on said semiconductor substrate with a second insulating film interposed, wherein

said protection film includes a film formed with a layer identical to said second insulating film.

8. The semiconductor device according to claim 7, further comprising a third insulating film formed so as to cover said first interconnection, wherein

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said protection film includes a film formed with a layer identical to said third insulating film.

9. The semiconductor device according to claim 8, further comprising a second interconnection formed on said third insulating film, and a fourth insulating film formed so as to cover said second interconnection, wherein

said protection film includes a film formed with a layer identical to said fourth insulating film.

10. An optical device comprising a semiconductor device according to claim 1.